

John L. Shew

2664

SEARCHED			
Class	Subclass	Date	Examiner
370	286	12/28/2005	JS
	287-291		
379	3,406.01	12/28/2005	JS
	406.02		
	406.03		
	406.04		
	406.05		
	406.06		
	406.07		
	406.08		
	406.09		
	406.1		
	406.11		
	406.12		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

[illegible]

Search Notes (continued)

Application/Control No.

09/981,978

Examiner

John L. Shew

Applicant(s)/Patent under
Reexamination

PARKER, BENJAMIN J.

Art Unit

2664

SEARCHED

Class	Subclass	Date	Examiner
379	406.13	12/28/2005	JS
	406.14		
	406.15		
	406.16		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR